

L Number	Hits	Search Text	DB	Time stamp
1	0	scan adj2 test and flip adj flop and circuit and conversion adj circuit and output adj2 storage	USPAT; EPO; JPO; DERWENT	2004/09/16 20:57
2	0	scan adj2 test and flip adj flop and conversion adj circuit and output adj2 storage	USPAT; EPO; JPO; DERWENT	2004/09/16 20:57
3	3	scan adj2 test and flip adj flop and conversion adj circuit and output near5 storage	USPAT; EPO; JPO; DERWENT	2004/09/16 20:57